

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-03
CB Certificate No.: 20003649 ITL

Schedule Number: IECQ-L ULTW 16.0003-03-S Rev No.: 8 Revision Date: 2025/07/09 Page 1 of 2

Appendix-1 (20003649 ITL) Schedule of Scope to Certificate of Approval

Tests	Standards/Procedures		
Transmission Electron Microscope - Electron Energy Loss Spectroscopy (TEM-EELS)	T-TEM-3		
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3		
Focused Ion Beam microscope (FIB)	T-FIB-3		
Emission Microscopy (EMMI)	T-EFA-3		
Emission Microscopy (EMMI)-InGaAs	T-EFA-3		
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3		
Optical Microscope (OM)	T-OMI-3		
3D Optical Microscope (3D OM)	T-LAB-3		
IC Layout Imaging	T-OMI-3		
Circuitry analysis	T-OMI-3		
Thermal Emission Microscope (THEMOS)	T-EFA-3		
Latch-up test	JESD78		
Human Body Mode (HBM)	ANSI/ESDA/JEDEC JS-001, ANSI/ESD STM 5.1, JESD22-A114, MIL-STD-883, AEC-Q100-002		
Machine Mode (MM)	ANSI/ESD S5.2, JESD22-A115, AEC-Q100-003		

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Charge Device Mode (CDM)	ANSI/ESD SP5.3.2, ANSI/ESD S5.3.1, JESD22-C101, ANSI/ESDA/JEDEC JS-002, AEC-Q100-011,			
Electrostatic discharge immunity test	IEC 61000-4-2			
Electrical Overstress (EOS)	IEC 61000-4-5			
Transmission Line Pulse (TLP)	ANSI/ESD STM5.5.1, ANSI/ESD SP5.5.2			
Wire Bonding	T-EFA-3			
IC Package	T-EFA-3			
Pull and shear test	MIL-STD-883 method 2011.9 MIL-STD-883 method 2023.7 AEC-Q100-001, EIA/JESD22-B116, JESD22-B117			
Electro-migration test	IPC TM650 2.6.25			
Conductive resistance test	IPC 9701			

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Technical Reviewer of DQS:		//	Date:	7/9/2025

